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Titolo	System Dependability and Analytics : Approaching System Dependability from Data, System and Analytics Perspectives / / edited by Long Wang, Karthik Pattabiraman, Catello Di Martino, Arjun Athreya, Saurabh Bagchi
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Nota di contenuto	Chapter 1. Introduction -- Chapter 2. Software Resilience (Long) -- Chapter 3. Large scale systems and data analytics (Saurabh) -- Chapter 4. Healthcare & CPS (Arjun) -- Chapter 5. Dependability Assessment (Karthik) -- Chapter 6. Personal reflections (Gene Robinson). .
Sommario/riassunto	This book comprises chapters authored by experts who are professors and researchers in internationally recognized universities and research institutions. The book presents the results of research and descriptions of real-world systems, services, and technologies. Reading this book, researchers, professional practitioners, and graduate students will gain a clear vision on the state of the art of the research and real-world practice on system dependability and analytics. The book is published in honor of Professor Ravishankar K. Iyer, the George and Ann Fisher

Distinguished Professor in the Department of Electrical and Computer Engineering at the University of Illinois at Urbana-Champaign (UIUC), Urbana, Illinois. Professor Iyer is ACM Fellow, IEEE Fellow, AAAS Fellow, and served as Interim Vice Chancellor of UIUC for research during 2008–2011. The book contains chapters written by many of his former students.

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